

650V N-Channel Enhancement Mode MOSFET

Description

The APJ150N60MP is CoolFET II MOSFET family that is utilizing charge balance technology for extremely low on-resistance and low gate charge performance. APJ150N60MP is suitable for applications which require superior power density and outstanding efficiency.

General Features

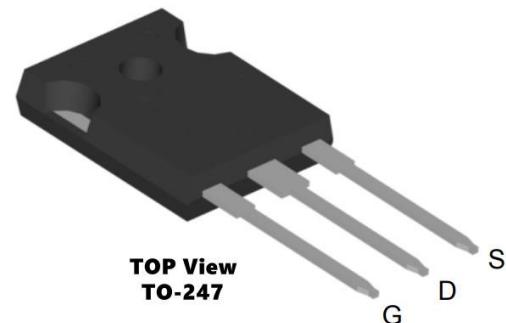
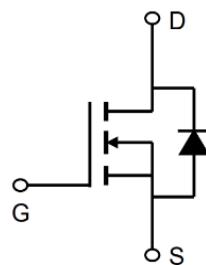
$V_{DS} = 600V$ (Type: 680V) $IDM = 150A$

$R_{DS(ON)} < 70m\Omega$ @ $V_{GS}=10V$ (Type: **62m Ω**)

Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
APJ150N60MP	TO-247-3L	APJ150N60MP XXX YYYY	300

Absolute Maximum Ratings ($T_c=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
$VDSS$	Drain-Source Voltage ($V_{GS} = 0V$)	600	V
ID	Continuous Drain Current	48	A
IDM	Pulsed Drain Current (note1)	150	A
VGS	Gate-Source Voltage	± 30	V
E_{AS}	Single Pulse Avalanche Energy (note2)	550	mJ
P_{tot}	Power Dissipation ($T_c = 25^\circ C$)	500	W
$T_{J, T_{stg}}$	Operating Junction and Storage Temperature Range	-55~+150	°C
R_{thJC}	Thermal Resistance, Junction-to-Case	0.25	°C/W
R_{thJA}	Thermal Resistance, Junction-to-Ambient	62	°C/W

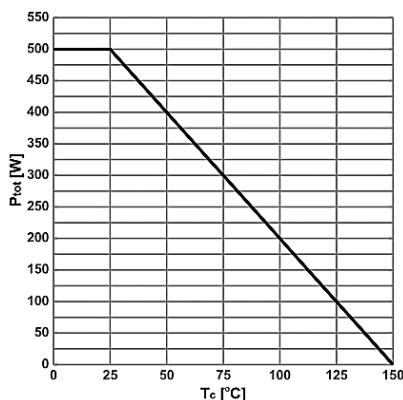
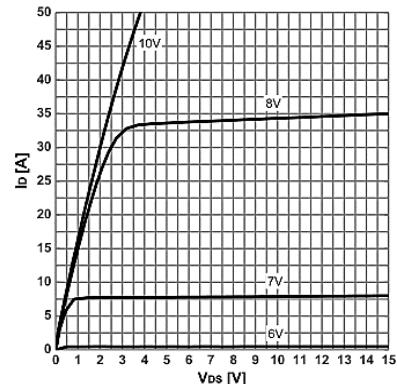


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Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

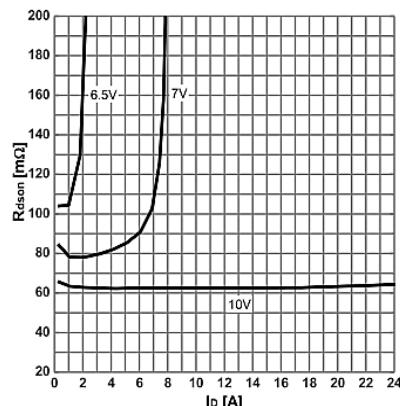
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
V(BR)DSS	Drain-source breakdown voltage	$V_{GS}=0\text{V}$, $I_D=1\text{mA}$	600	680	-	V
V(GS)th	Gate threshold voltage	$V_{DS}=V_{GS}$, $I_D=1\text{mA}$	3	4	5	V
IDSS	Zero gate voltage drain current	$V_{DS}=600\text{V}$, $V_{GS}=0\text{V}$, $T_J=25^\circ\text{C}$	-	-	10	μA
IGSS	Gate-source leakage current	$V_{GS}=\pm 30\text{V}$, $V_{DS}=0\text{V}$	-	-	± 100	nA
RDS(on)	Drain-source on-state resistance	$V_{GS}=10\text{V}$, $I_D=23.5\text{A}$, $T_J=25^\circ\text{C}$	-	62	70	$\text{m}\Omega$
RG	Gate resistance	$V_{DD}=0\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	-	3.6	-	Ω
Ciss	Input capacitance	$V_{GS}=0\text{V}$, $V_{DS}=50\text{V}$, $f=250\text{kHz}$	-	3750	-	pF
Coss	Output capacitance		-	110	-	pF
Crss	Reverse transfer capacitance		-	4	-	pF
td(on)	Turn-on delay time	$V_{DD}=400\text{V}$, $V_{GS}=10\text{V}$, $I_D=23\text{A}$	-	87	-	ns
tr	Rise time		-	66	-	ns
td(off)	Turn-off delay time		-	125	-	ns
tf	Fall time		-	72	-	ns
Qgs	Gate to source charge	$V_{DD}=400\text{V}$, $I_D=23\text{A}$, $V_{GS}=0$ to 10V	-	20	-	nC
Qgd	Gate to drain charge		-	16	-	nC
Qg	Gate charge total		-	70	-	nC
Vplateau	Gate plateau voltage	$V_{DD}=400\text{V}$, $I_D=23\text{A}$, $V_{GS}=0$ to 10V	-	5.3	-	V
VSD	Diode forward voltage	$V_{GS}=0\text{V}$, $I_F=23\text{A}$, $T_f=25^\circ\text{C}$	-	0.88	-	V
trr	Reverse recovery time	$V_R=100\text{V}$, $I_F=23\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$	-	147	-	ns
Qrr	Reverse recovery charge		-	1.32	-	μC
Irrm	Peak reverse recovery current		-	17	-	A

Note :

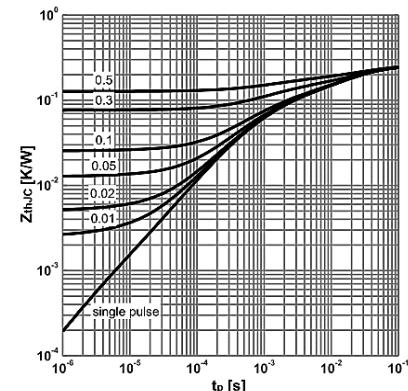
- 1、The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2、The EAS data shows Max. rating . L=0.5mH, IAS =7A, VDD =50V, RG=25Ω
- 3、The test condition is Pulse Test: ISD ≤ ID, di/dt = 100A/us, VDD≤ BVDS, Starting at TJ =25°C
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

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Typical Characteristics

Figure1: Power dissipation (Non FullPAK)

Figure2: output characteristics

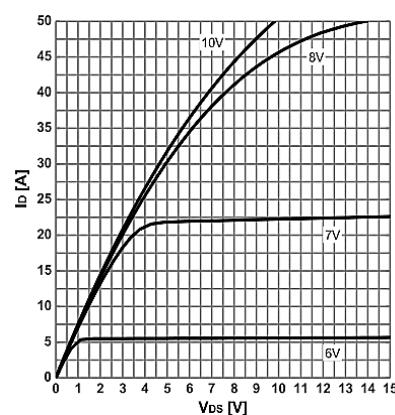
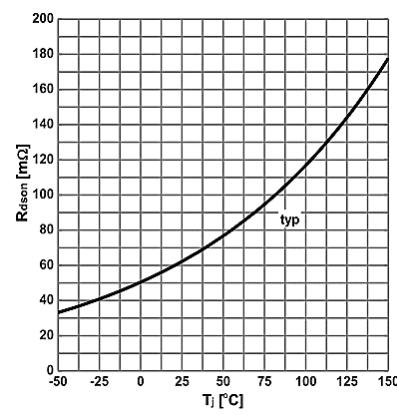
ID=f(VDS); Tj=25°C; parameter: VGS

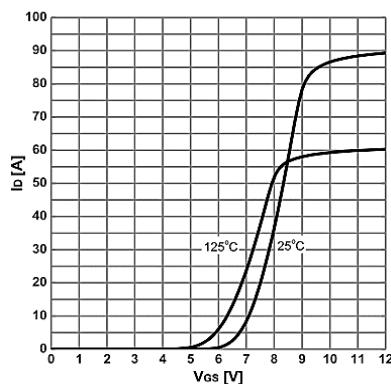
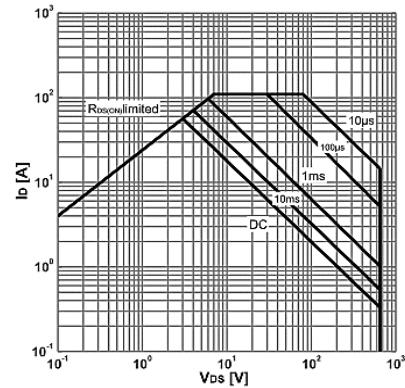
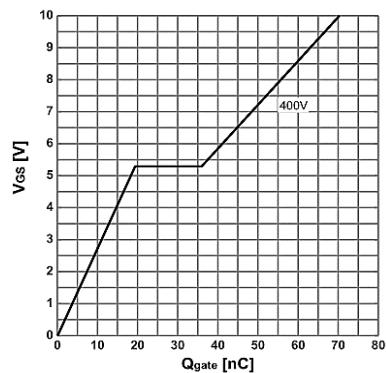
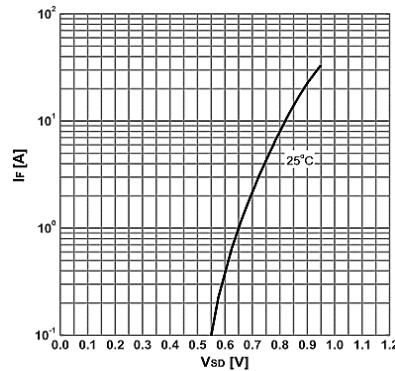
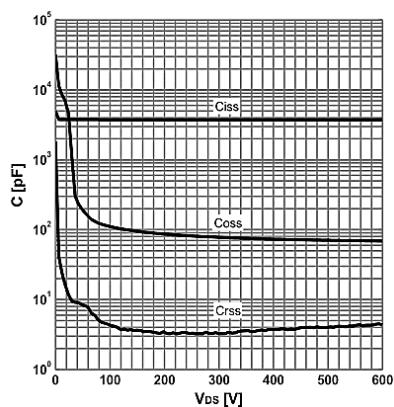
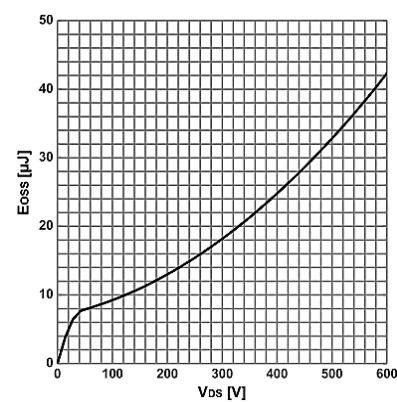

Figure3: Typ. drain-source on-state resistance

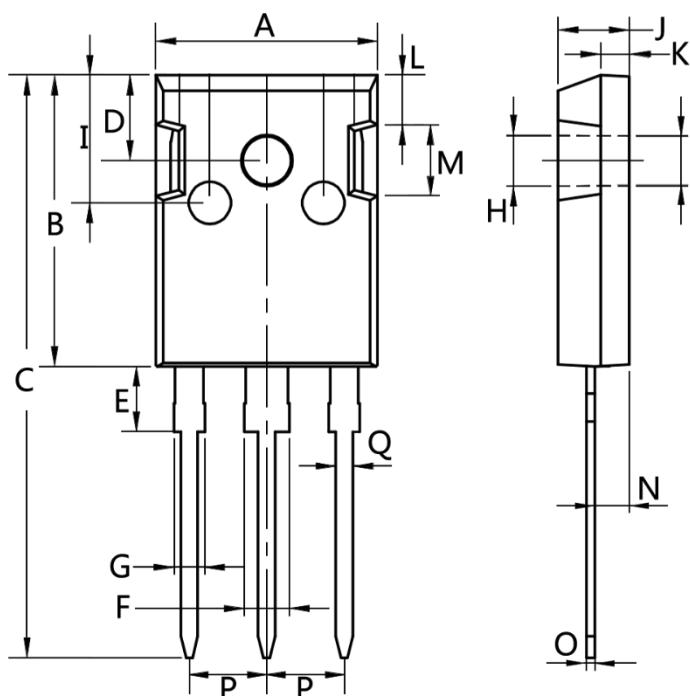
RDS (on)=f(ID); Tj=25°C; parameter: VGS


Figure4:Max. transient thermal impedance

Ptot=f(TC)


Figure5: Type. output characteristics
ID =f(VDS); Tj=125°C; parameter: VGS

Figure6: Max. transient thermal impedance
RDS (on)=f(Tj); ID=23.5A; VGS =10V

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Figure 7: Typ. transfer characteristics
 $ID=f(V_{GS})$; $V_{DS}=20\text{V}$; parameter: T_j

Figure 8 : Safe operating area (Non FullPAK)
 $ID=f(V_{DS})$; $T_j=25^\circ\text{C}$; $D=0$; parameter: t_p

Figure 9: Typ. gate charge
 $V_{GS}=f(Q_{gate})$; $ID=25\text{A}$ pulsed; $V_{DS}=400\text{V}$

Figure 10: Forward characteristics of reverse diode
 $I_F=f(V_{SD})$; parameter: T_j

Figure 11: Typ. capacitances
 $C=f(V_{DS})$; $V_{GS}=0\text{V}$; $f=250\text{kHz}$

Figure 12: Typ. Coss stored energy
 $E_{OSS}=f(V_{DS})$

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Package Mechanical Data-TO-247-3L


Dim.	Min.	Max.
A	15.0	16.0
B	20.0	21.0
C	41.0	42.0
D	5.0	6.0
E	4.0	5.0
F	2.5	3.5
G	1.75	2.5
H	3.0	3.5
I	8.0	10.0
J	4.9	5.1
K	1.9	2.1
L	3.5	4.0
M	4.75	5.25
N	2.0	3.0
O	0.55	0.75
P	Typ 5.08	
Q	1.2	1.3